

PATENT CLAIMS

1. A method for the monitoring of a manufacturing process of a plurality of physical objects,
in which an analysis is performed by using values of at least one process parameter of the manufacturing process of the physical object;
in which, as a result of the analysis, when they do not satisfy a prescribed selection criterion, physical objects are marked in such a way that the associated physical objects are to be sent for a special measurement.
2. The method as claimed in claim 1, in which the physical object is a wafer.
3. The method as claimed in claim 1 or 2, in which the analysis is a statistical analysis.
4. The method as claimed in one of claims 1 to 3, in which the values of the at least one process parameter are measured when the physical object is being manufactured.
5. The method as claimed in one of claims 1 to 4, in which at least one marked physical object is sent for a special measurement.
6. The method as claimed in claim 5, in which the special measurement is a measurement for checking the quality of the physical object marked.
7. The method as claimed in one of claims 1 to 6, in which the physical objects not marked are further treated according to the manufacturing process.
8. The method as claimed in one of claims 1 to 7, in which the selection criterion is a quality characteristic of the manufacturing process.

9. The method as claimed in one of claims 1 to 8, in which the selection criterion is considered as not satisfied if a value of the at least one process parameter goes above or below a prescribed limit value.

10. A device for the monitoring of a manufacturing process of a plurality of physical objects with a processor which is set up in such a way that the following method steps can be carried out:

performance of an analysis by using values of at least one process parameter of the manufacturing process of the physical object;

marking of physical objects when, as a result of the analysis, a prescribed selection criterion is not satisfied, so that the associated physical objects are to be sent for special treatments.

11. A computer-readable storage medium, in which a program for the monitoring of a manufacturing process of a plurality of physical objects is stored, which program has the following method steps when it is run by a processor:

performance of an analysis by using values of at least one process parameter of the manufacturing process of the physical object;

marking of physical objects when, as a result of the analysis, a prescribed selection criterion is not satisfied, so that the associated physical objects are to be sent for special treatments.

12. A computer program element for the monitoring of a manufacturing process of a plurality of physical objects, which has the following method steps when it is run by a processor:

performance of an analysis by using values of at least one process parameter of the manufacturing process of the physical object;

marking of physical objects when, as a result of the analysis, a prescribed selection criterion is not satisfied, so that the associated physical objects are to be sent for special treatments.